

To: T10 Technical Committee  
From: Mark Overby, NVIDIA Corporation (moverby@nvidia.com)  
Date: 13 September 2005  
Subject: T10/05-360r0 SPC-4: Extended self test completion time value update

### **Revision History**

Revision 0 - Initial draft of document

Revision 1 - Updated title and date

From Rob Elliot comments: Clarified new text with "extended self-test" instead of "self-test". Removed "will".

### **Related Documents**

SPC-4 (T10/1731-D) Revision 1a

## **1 Overview**

This proposal adds language to the definition of the extended self test completion time field, from the control mode page, to indicate how to interpret a value of FFFFh in that field.

## **2 Document Changes**

### **2.1 Changes to SPC-4 (T10/1731-D r1a)**

Modify the paragraph from SPC-4, in subclause 7.4.6, describing the extended self test completion time field to read as follows.

The EXTENDED SELF-TEST COMPLETION TIME field contains advisory data that is the time in seconds that the device server requires to complete an extended self-test when the device server is not interrupted by subsequent commands and no errors occur during processing of the self-test. The application client should expect this time to increase significantly if other commands are sent to the logical unit while a self-test is in progress or if errors occur during the processing of the self-test. Device servers supporting SELF-TEST CODE field values other than 000b for the SEND DIAGNOSTIC command (see 6.28) shall support the EXTENDED SELF-TEST COMPLETION TIME field. The EXTENDED SELF-TEST COMPLETION TIME field is not changeable. [A value of FFFFh indicates that the extended self-test takes FFFFh seconds or longer.](#)